

IMW120R220M1H

英飞凌 CoolSiC™ 1200V SiC 沟槽 MOSFET

碳化硅 MOSFET

特性

- 开关损耗非常低
- 无拐点导通特性
- 宽栅源电压范围
- 基准栅极阈值电压, $V_{GS(th)} = 4.5V$
- 0V 关断栅极电压, 实现简单便捷的栅极驱动
- 完全可控的 dV/dt
- 坚固的体二极管, 适用于硬换向
- 关断损耗不受温度影响

优点

- 提高效率
- 实现更高的频率
- 增加功率密度
- 减少冷却工作量
- 降低系统复杂性和成本

潜在应用

- 能源生产
 - 光伏组串逆变器和光伏优化器
- 工业供电
 - 工业级不间断电源 (UPS)
 - 工业开关电源
- 基础设施 – 充电
 - 充电器

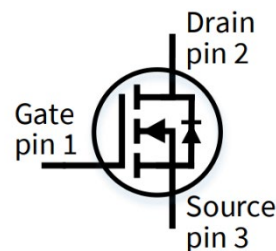
产品验证

符合 JEDEC47/20/22 相关测试的工业应用要求

表 1 主要性能及封装参数

Type	V_{DS}	I_D <small>$T_C = 25^\circ C, R_{th(j-c, max)}$</small>	$R_{DS(on)}$ <small>$T_{vj} = 25^\circ C, I_D = 4A, V_{GS} = 18V$</small>	$T_{vj, max}$	Marking	Package
IMW120R220M1H	1200V	13A	220mΩ	175°C	12M1H220	PG-TO247-3

本数据手册的原文使用英文撰写。为方便起见, 英飞凌提供了译文; 由于翻译过程中可能使用了自动化工具, 英飞凌不保证译文的准确性。为确认准确性, 请务必访问 infineon.com 参考最新的英文版本 (控制文档)。



目录

目录

特性	1
优点	1
潜在应用	1
产品验证	1
目录	2
1 最大额定值.....	3
2 热阻.....	4
3 电气特性	5
3.1 静态特性.....	5
3.2 动态特性.....	6
3.3 开关特性.....	7
4 电气特性图.....	8
5 封装图	14
6 测试条件	15
修订记录	16

最大额定值

1 最大额定值

注意：为了获得最佳的使用寿命和可靠性，英飞凌建议运行条件不超过本数据手册中所述最大额定值的 80%。

表 2 最大额定值

Parameter	Symbol	Value	Unit
Drain-source voltage, $T_{vj} \geq 25^\circ\text{C}$	V_{DS}	1200	V
DC drain current for $R_{th(j-c,max)}$, limited by T_{vjmax} , $V_{GS} = 18\text{V}$, $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	I_D	13 9.5	A
Pulsed drain current, t_p limited by T_{vjmax} , $V_{GS} = 18\text{V}$	$I_{D,pulse1}$	21	A
DC body diode forward current for $R_{th(j-c,max)}$, limited by T_{vjmax} , $V_{GS} = 0\text{V}$ $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	I_{SD}	13 9.3	A
Pulsed body diode current, t_p limited by T_{vjmax}	$I_{SD,pulse1}$	32	A
Gate-source voltage ² Max transient voltage, < 1% duty cycle Recommended turn-on gate voltage Recommended turn-off gate voltage	V_{GS} $V_{GS,on}$ $V_{GS,off}$	-7... 23 15... 18 0	V
Short-circuit withstand time $V_{DD} = 800\text{V}$, $V_{DS,peak} < 1200\text{V}$, $V_{GS,on} = 15\text{V}$, $T_{j,start} = 25^\circ\text{C}$	t_{sc}	3	μs
Power dissipation, limited by T_{vjmax} $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	P_{tot}	75 37.5	W
Virtual junction temperature	T_{vj}	-55... 175	$^\circ\text{C}$
Storage temperature	T_{stg}	-55... 150	$^\circ\text{C}$
Soldering temperature, wave soldering only allowed at leads, 1.6mm (0.063 in.) from case for 10 s	T_{sold}	260	$^\circ\text{C}$
Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

¹ 经过设计验证

² **重要提示：**正、负栅源电压的选择会影响器件的长期性能。为确保设备在计划使用寿命内正常运行，请务必研读 [《应用笔记 AN2018-09》](#) 中描述的设计指南。

热阻

2 热阻

表 3

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
MOSFET/body diode thermal resistance, junction – case	$R_{th(j-c)}$		-	1.5	2	K/W
Thermal resistance, junction – ambient	$R_{th(j-a)}$	leaded	-	-	62	K/W

电气特性

3 电气特性

3.1 静态特性

表 4 静态特性 (测于 $T_{vj} = 25^{\circ}\text{C}$ 时, 除非另有规定)

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS} = 18\text{V}, I_D = 4\text{A}, T_{vj} = 25^{\circ}\text{C}$	-	220	294	mΩ
		$T_{vj} = 100^{\circ}\text{C}$	-	280	-	
		$T_{vj} = 175^{\circ}\text{C}$	-	416	-	
		$V_{GS} = 15\text{V}, I_D = 4\text{A}, T_{vj} = 25^{\circ}\text{C}$	-	280	372	
Body diode forward voltage	V_{SD}	$V_{GS} = 0\text{V}, I_{SD} = 4\text{A}, T_{vj} = 25^{\circ}\text{C}$	-	4.1	5.2	V
		$T_{vj} = 100^{\circ}\text{C}$	-	4.0	-	
		$T_{vj} = 175^{\circ}\text{C}$	-	3.9	-	
Gate-source threshold voltage	$V_{GS(th)}$	(tested after 1 ms pulse at $V_{GS} = 20\text{V}$) $I_D = 1.6\text{mA}, V_{DS} = V_{GS}$ $T_{vj} = 25^{\circ}\text{C}$	3.5	4.5	5.7	V
		$T_{vj} = 175^{\circ}\text{C}$	-	3.6	-	
Zero gate voltage drain current	I_{DSS}	$V_{GS} = 0\text{V}, V_{DS} = 1200\text{V}, T_{vj} = 25^{\circ}\text{C}$	-	0.2	95	μA
		$T_{vj} = 175^{\circ}\text{C}$	-	0.6	-	
Gate-source leakage current	I_{GSS}	$V_{GS} = 23\text{V}, V_{DS} = 0\text{V}$	-	-	100	nA
		$V_{GS} = -7\text{V}, V_{DS} = 0\text{V}$	-	-	-100	nA
Transconductance	g_{fs}	$V_{DS} = 20\text{V}, I_D = 4\text{A}$	-	2	-	S
Internal gate resistance	$R_{G,int}$	$f = 1\text{MHz}, V_{AC} = 25\text{mV}$	-	22	-	Ω

电气特性

3.2 动态特性

表 5 动态特性 (测于 $T_{vj} = 25^{\circ}\text{C}$, 除非另有规定)

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Input capacitance	C_{iss}	$V_{DD} = 800\text{V}, V_{GS} = 0\text{V},$ $f = 1\text{MHz}, V_{AC} = 25\text{mV}$	-	289	-	pF
Output capacitance	C_{oss}		-	16	-	
Reverse capacitance	C_{rss}		-	2	-	
C_{oss} stored energy	E_{oss}		-	6	-	μJ
Total gate charge	Q_G	$V_{DD} = 800\text{V}, I_D = 4\text{A},$ $V_{GS} = 0/18\text{V}, \text{turn-on pulse}$	-	8.5	-	nC
Gate to source charge	$Q_{GS,pl}$		-	2.5	-	
Gate to drain charge	Q_{GD}		-	2	-	

电气特性

3.3 开关特性

表 6 开关特性，感性负载⁴

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
MOSFET Characteristics, $T_{vj} = 25^{\circ}\text{C}$						
Turn-on delay time	$t_{d(\text{on})}$	$V_{DD} = 800\text{V}$, $I_D = 4\text{A}$, $V_{GS} = 0/18\text{V}$, $R_{G,\text{ext}} = 2\Omega$, $L_{\sigma} = 40\text{nH}$, diode: body diode at $V_{GS} = 0\text{V}$ see Fig. E	-	5	-	ns
Rise time	t_r		-	1.4	-	
Turn-off delay time	$t_{d(\text{off})}$		-	10	-	
Fall time	t_f		-	14	-	
Turn-on energy	E_{on}		-	61	-	μJ
Turn-off energy	E_{off}		-	7	-	
Total switching energy	E_{tot}		-	68	-	
Body Diode, $T_{vj} = 25^{\circ}\text{C}$						
Diode reverse recovery charge	Q_{rr}	$V_{DD} = 800\text{V}$, $I_{SD} = 4\text{A}$, V_{GS} at diode = 0V , $di/dt = 1000\text{A}/\mu\text{s}$, Q_{rr} includes also Q_C , see Fig. C	-	78	-	nC
Diode peak reverse recovery current	I_{rrm}		-	1.4	-	A
MOSFET Characteristics, $T_{vj} = 175^{\circ}\text{C}$						
Turn-on delay time	$t_{d(\text{on})}$	$V_{DD} = 800\text{V}$, $I_D = 4\text{A}$, $V_{GS} = 0/18\text{V}$, $R_{G,\text{ext}} = 2\Omega$, $L_{\sigma} = 40\text{nH}$, diode: body diode at $V_{GS} = 0\text{V}$ see Fig. E	-	5	-	ns
Rise time	t_r		-	3.5	-	
Turn-off delay time	$t_{d(\text{off})}$		-	10	-	
Fall time	t_f		-	14	-	
Turn-on energy	E_{on}		-	76	-	μJ
Turn-off energy	E_{off}		-	7	-	
Total switching energy	E_{tot}		-	83	-	
Body Diode Characteristics, $T_{vj} = 175^{\circ}\text{C}$						
Diode reverse recovery charge	Q_{rr}	$V_{DD} = 800\text{V}$, $I_{SD} = 4\text{A}$, V_{GS} at diode = 0V , $di/dt = 1000\text{A}/\mu\text{s}$, Q_{rr} includes also Q_C , see Fig. C	-	98	-	nC
Diode peak reverse recovery current	I_{rrm}		-	2	-	A

⁴ 该芯片技术的特征斜率高达200 kV/ μs 。测量的 dV/dt 受到测量测试设置和封装的限制。

电气特性图

4 电气特性图

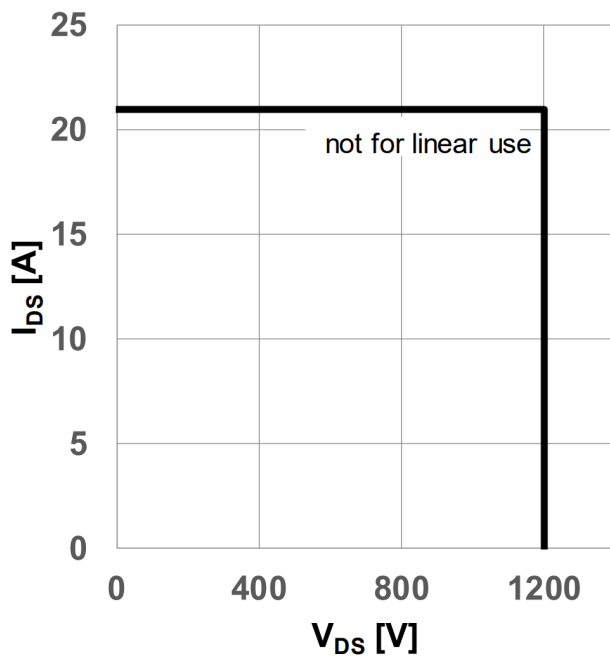


Figure 1 Safe operating area (SOA)
($V_{GS} = 0/18V$, $T_c = 25^\circ C$, $T_j \leq 175^\circ C$)

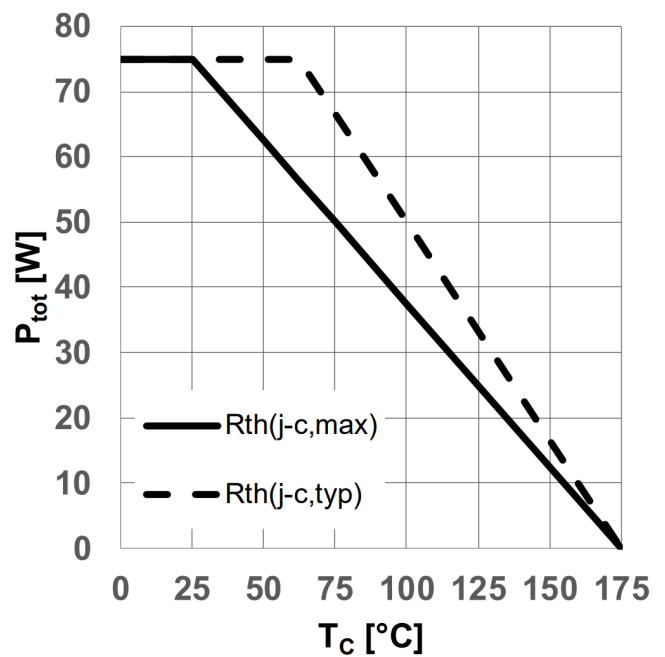


Figure 2 Power dissipation as a function of case temperature limited by bond wire
($P_{tot} = f(T_c)$)

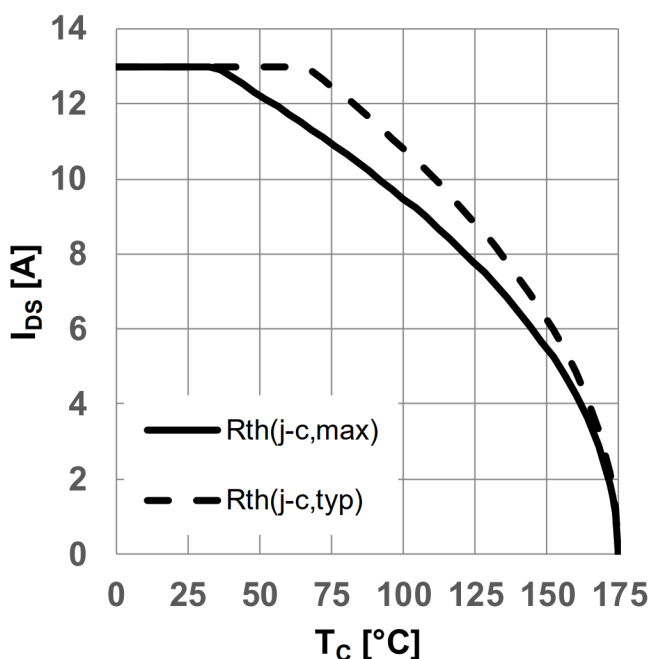


Figure 3 Maximum DC drain to source current as a function of case temperature limited by bond wire ($I_{DS} = f(T_c)$)

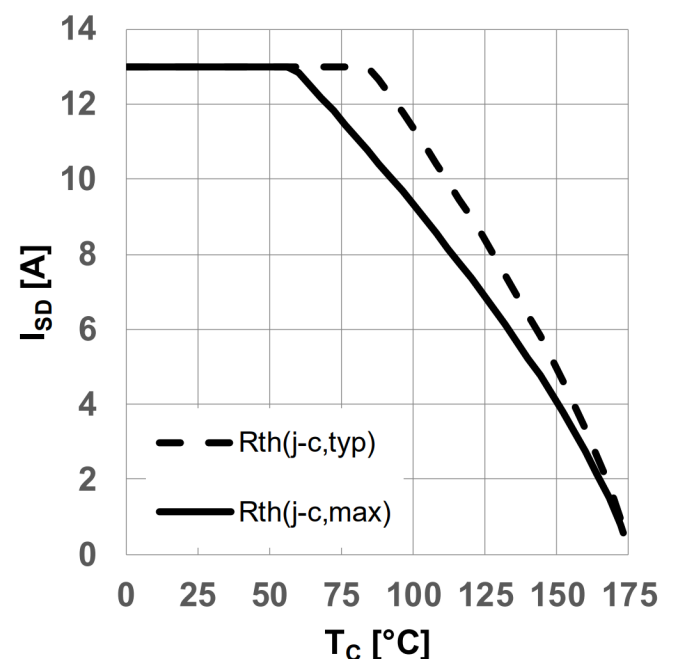


Figure 4 Maximum source to drain current as a function of case temperature limited by bond wire ($I_{SD} = f(T_c)$, $V_{GS} = 0V$)

电气特性图

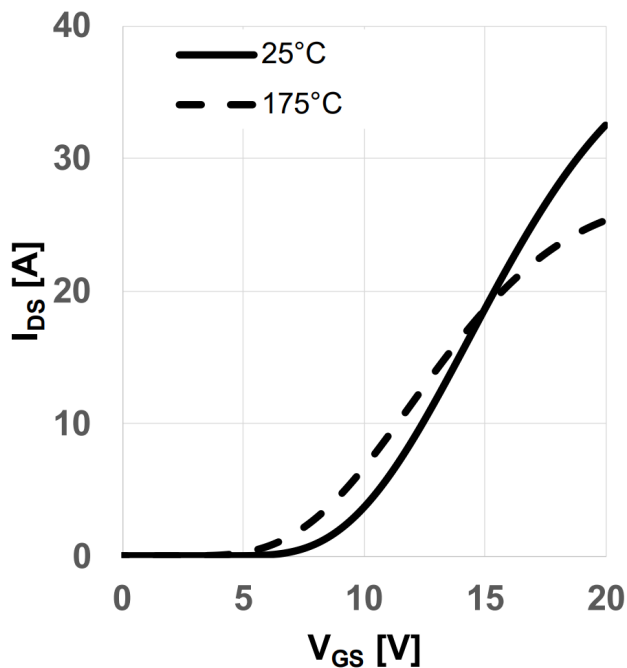


Figure 5 Typical transfer characteristic
($I_{DS} = f(V_{GS})$, $V_{DS} = 20V$, $t_P = 20\mu s$)

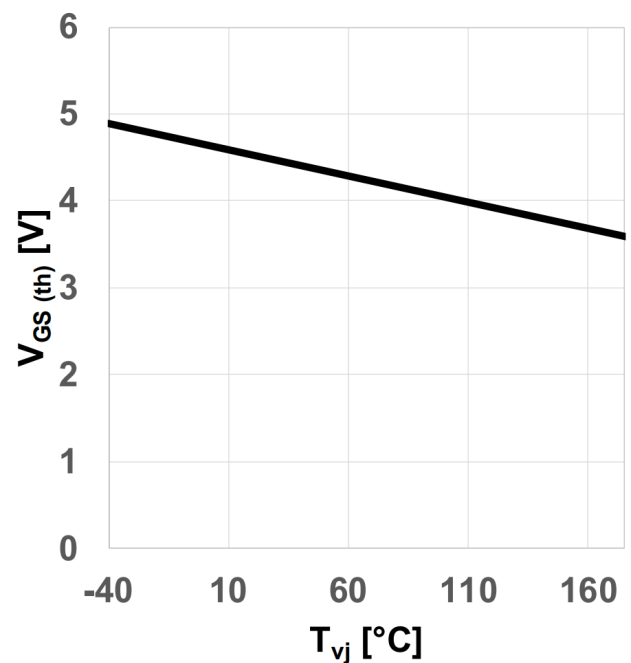


Figure 6 Typical gate-source threshold voltage as a function of junction temperature
($V_{GS(th)} = f(T_{vj})$, $I_{DS} = 1.6mA$, $V_{GS} = V_{DS}$)

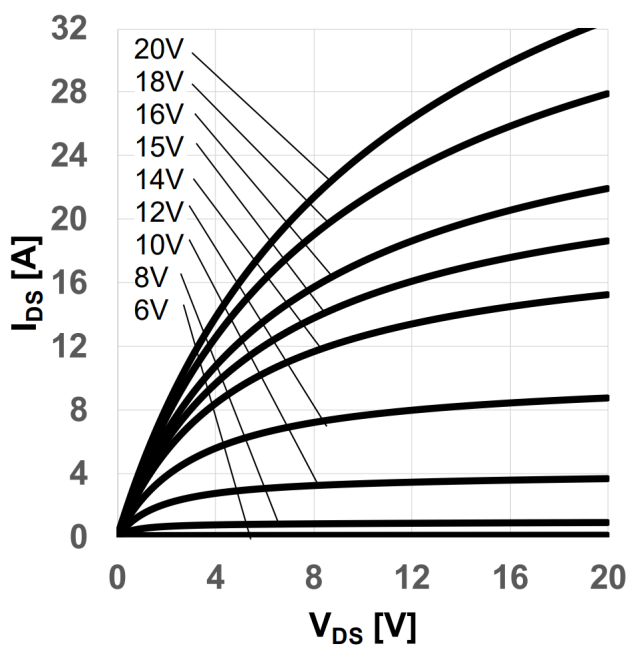


Figure 7 Typical output characteristic, V_{GS} as parameter
($I_{DS} = f(V_{DS})$, $T_{vj} = 25^\circ C$, $t_P = 20\mu s$)

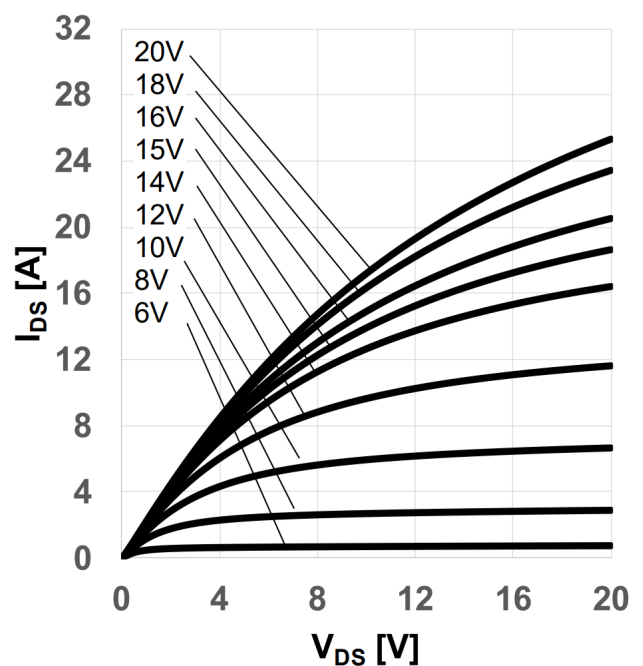


Figure 8 Typical output characteristic, V_{GS} as parameter
($I_{DS} = f(V_{DS})$, $T_{vj} = 175^\circ C$, $t_P = 20\mu s$)

电气特性图

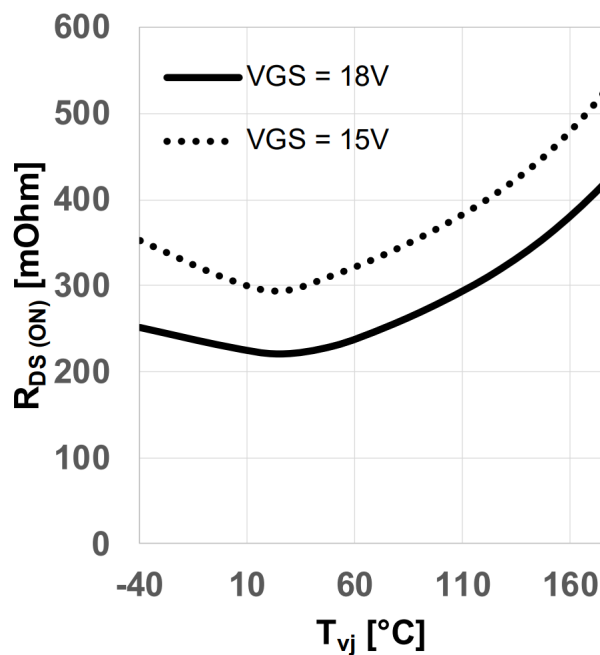


Figure 9 Typical on-resistance as a function of junction temperature
 $(R_{DS(on)} = f(T_{vj}), I_{DS} = 4A)$

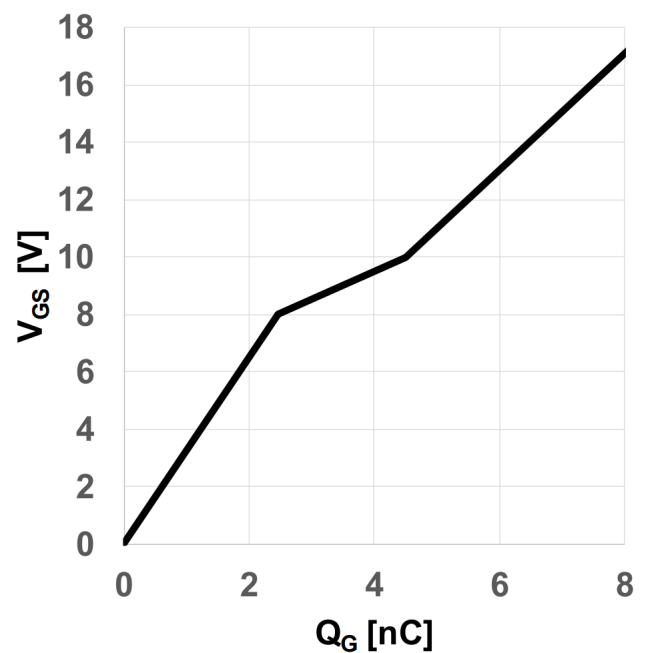


Figure 10 Typical gate charge
 $(V_{GS} = f(Q_G), I_{DS} = 4A, V_{DS} = 800V, \text{turn-on pulse})$

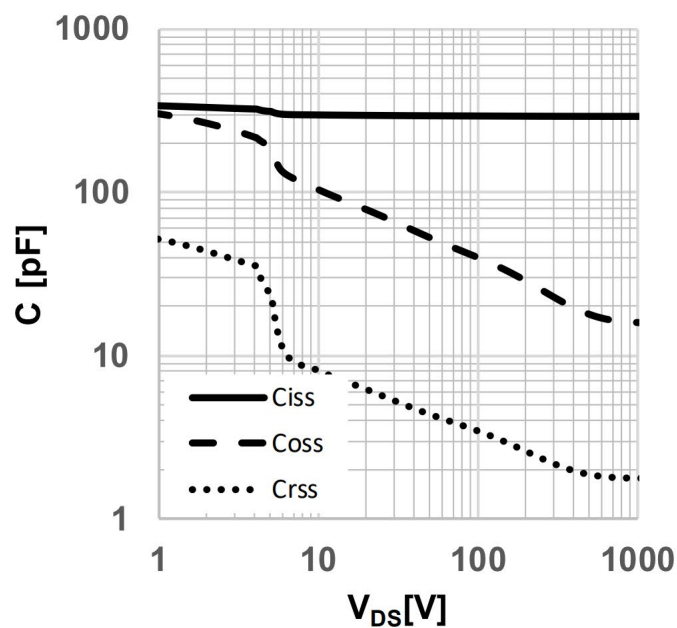


Figure 11 Typical capacitance as a function of drain-source voltage
 $(C = f(V_{DS}), V_{GS} = 0V, f = 1MHz)$

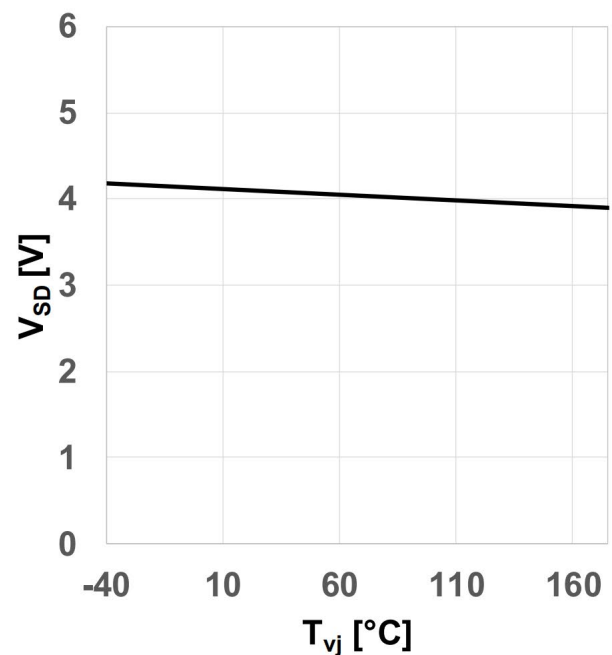


Figure 12 Typical body diode forward voltage as function of junction temperature
 $(V_{SD} = f(T_{vj}), V_{GS} = 0V, I_{SD} = 4A)$

电气特性图

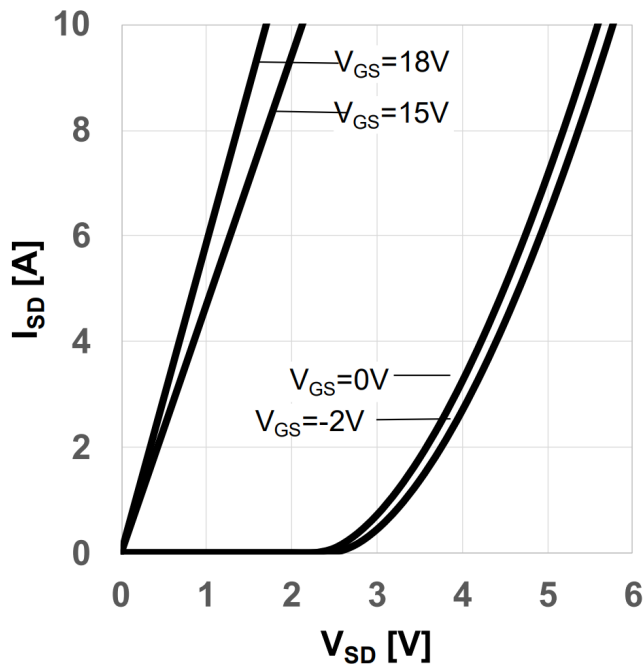


Figure 13 Typical body diode forward current as function of forward voltage, V_{GS} as parameter

($I_{SD} = f(V_{SD})$, $T_{vj} = 25^\circ\text{C}$, $t_P = 20\mu\text{s}$)

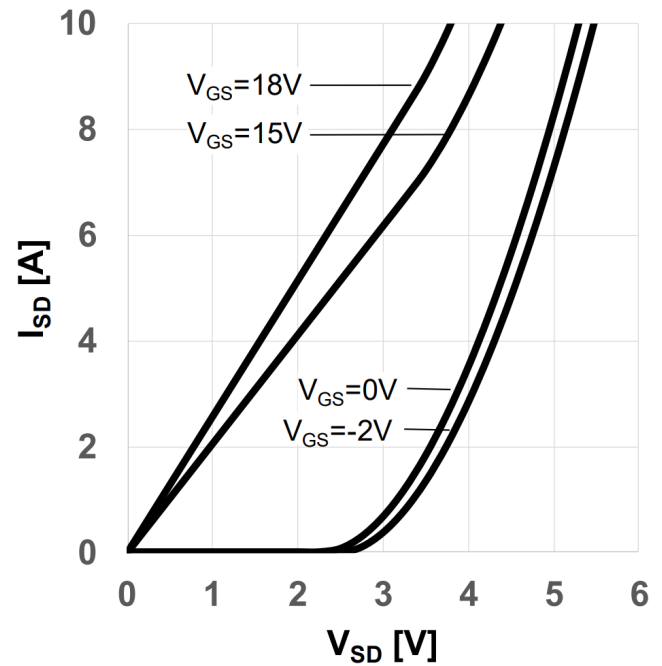


Figure 14 Typical body diode forward current as function of forward voltage, V_{GS} as parameter

($I_{SD} = f(V_{SD})$, $T_{vj} = 175^\circ\text{C}$, $t_P = 20\mu\text{s}$)

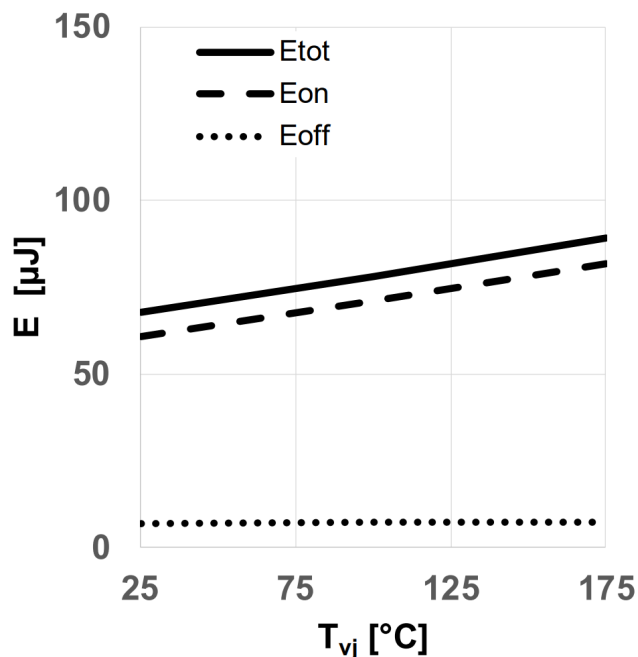


Figure 15 Typical switching energy losses as a function of junction temperature
($E = f(T_{vj})$, $V_{DD} = 800\text{V}$, $V_{GS} = 0\text{V}/18\text{V}$, $R_{G,ext} = 2\Omega$, $I_D = 4\text{A}$, ind. load, test circuit in Fig. E, diode: body diode at $V_{GS} = 0\text{V}$)

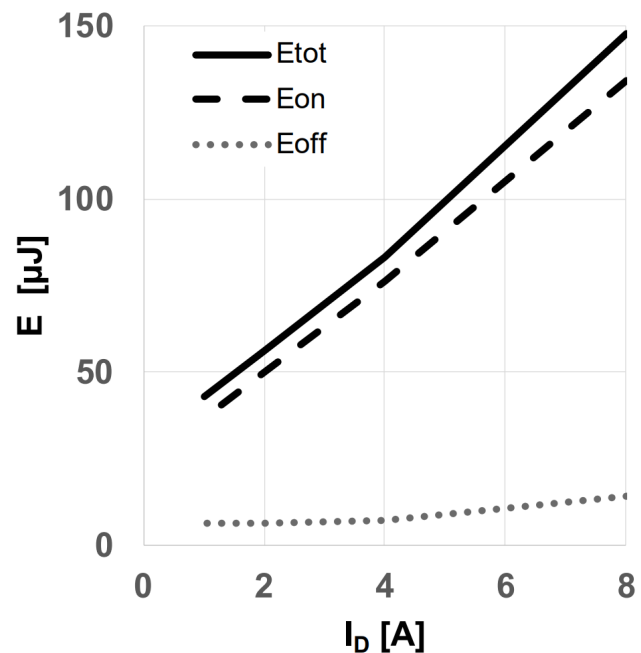


Figure 16 Typical switching energy losses as a function of drain-source current
($E = f(I_{DS})$, $V_{DD} = 800\text{V}$, $V_{GS} = 0\text{V}/18\text{V}$, $R_{G,ext} = 2\Omega$, $T_{vj} = 175^\circ\text{C}$, ind. load, test circuit in Fig. E, diode: body diode at $V_{GS} = 0\text{V}$)

电气特性图

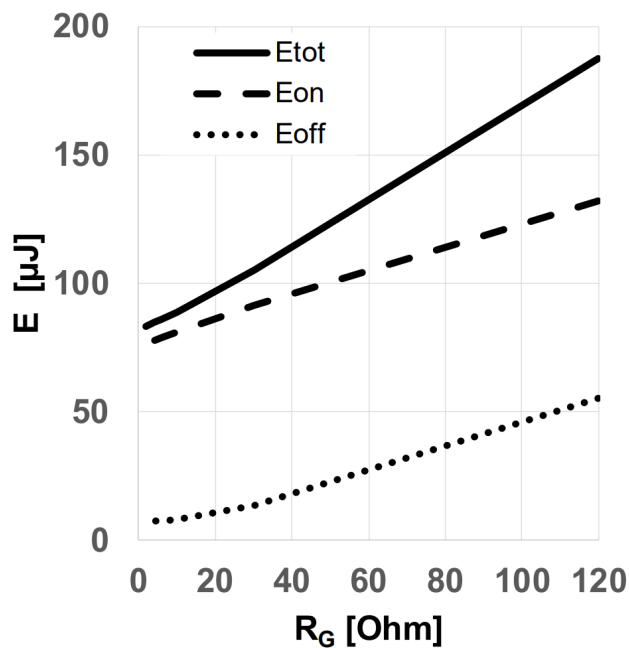


Figure 17 Typical switching energy losses as a function of gate resistance
 $(E = f(R_{G,ext}), V_{DD} = 800V, V_{GS} = 0V/18V, I_D = 4A, T_{vj} = 175^\circ C, \text{ind. load, test circuit in Fig. E, diode: body diode at } V_{GS} = 0V)$

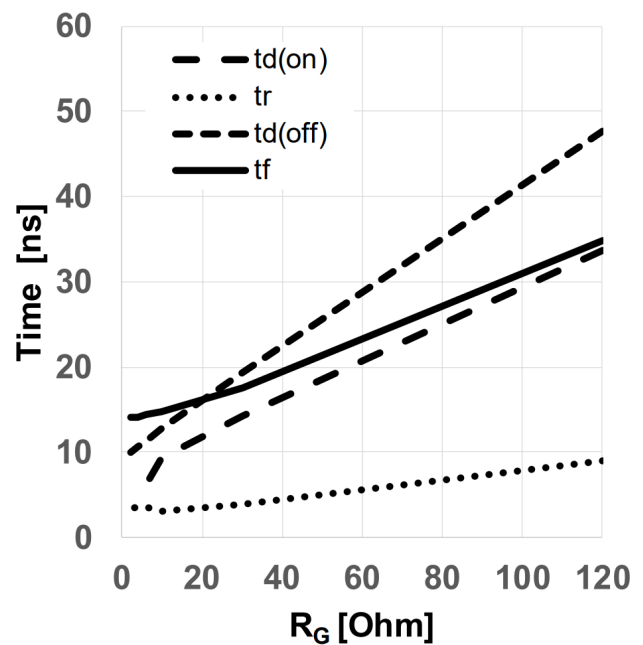


Figure 18 Typical switching times as a function of gate resistor
 $(t = f(R_{G,ext}), V_{DD} = 800V, V_{GS} = 0V/18V, I_D = 4A, T_{vj} = 175^\circ C, \text{ind. load, test circuit in Fig. E, diode: body diode at } V_{GS} = 0V)$

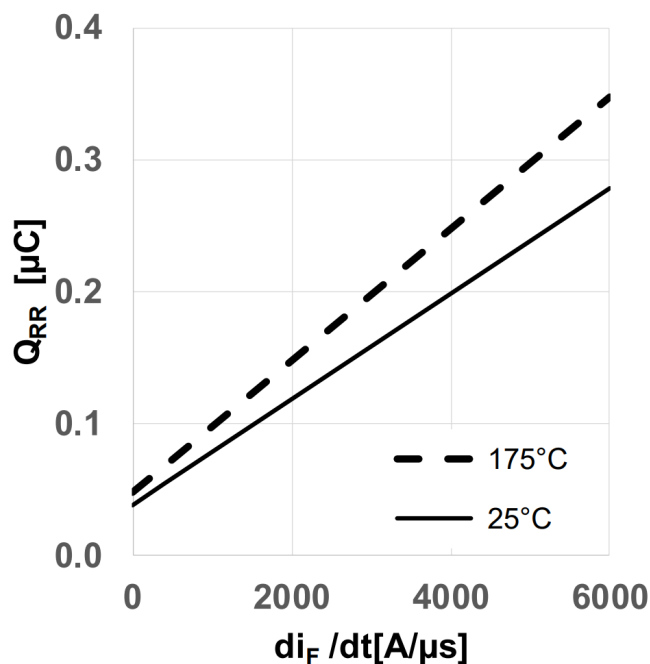


Figure 19 Typical reverse recovery charge as a function of diode current slope
 $(Q_{rr} = f(di_F/dt), V_{DD} = 800V, V_{GS} = 0V/18V, I_D = 4A, \text{ind. load, test circuit in Fig. E, body diode at } V_{GS} = 0V)$

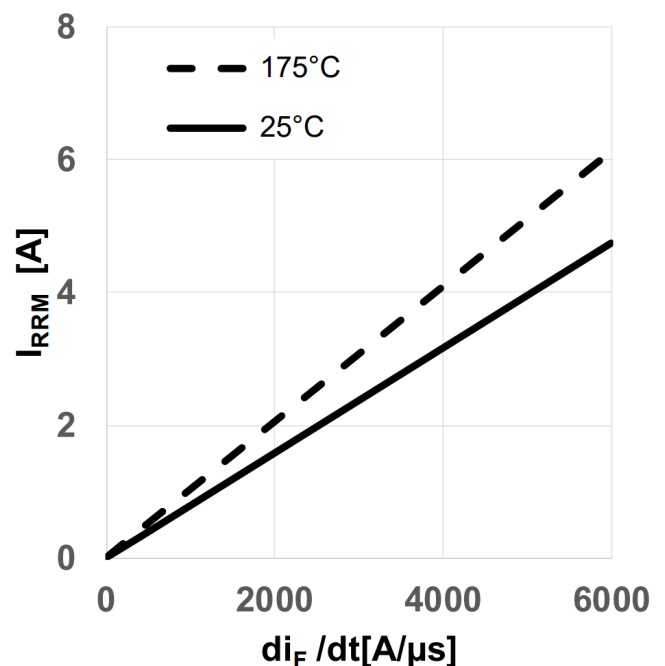


Figure 20 Typical reverse recovery current as a function of diode current slope
 $(I_{rrm} = f(di_F/dt), V_{DD} = 800V, V_{GS} = 0V/18V, I_D = 4A, \text{ind. load, test circuit in Fig. E, body diode at } V_{GS} = 0V)$

电气特性图

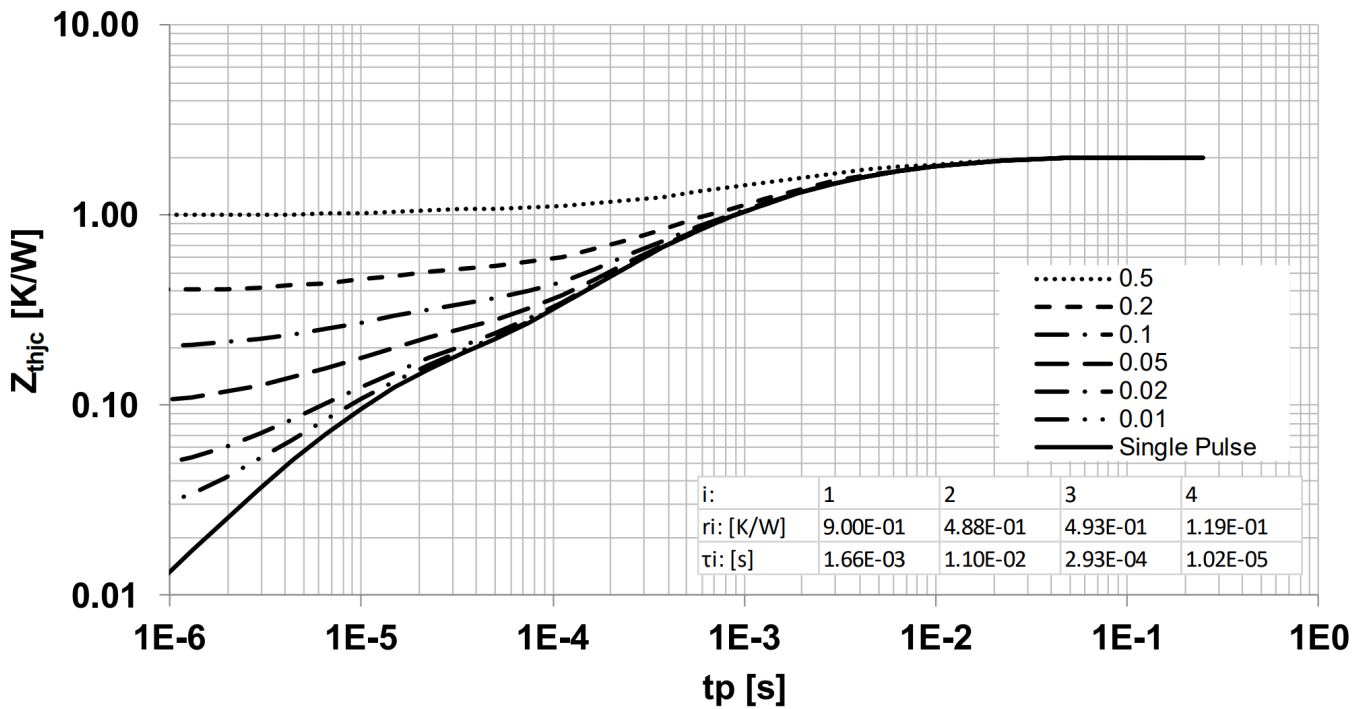


Figure 21 Max. transient thermal resistance (MOSFET/diode)
($Z_{th(j-c,max)} = f(t_p)$, parameter $D = t_p/T$, thermal equivalent circuit in Fig. D)

封装图

5 封装图

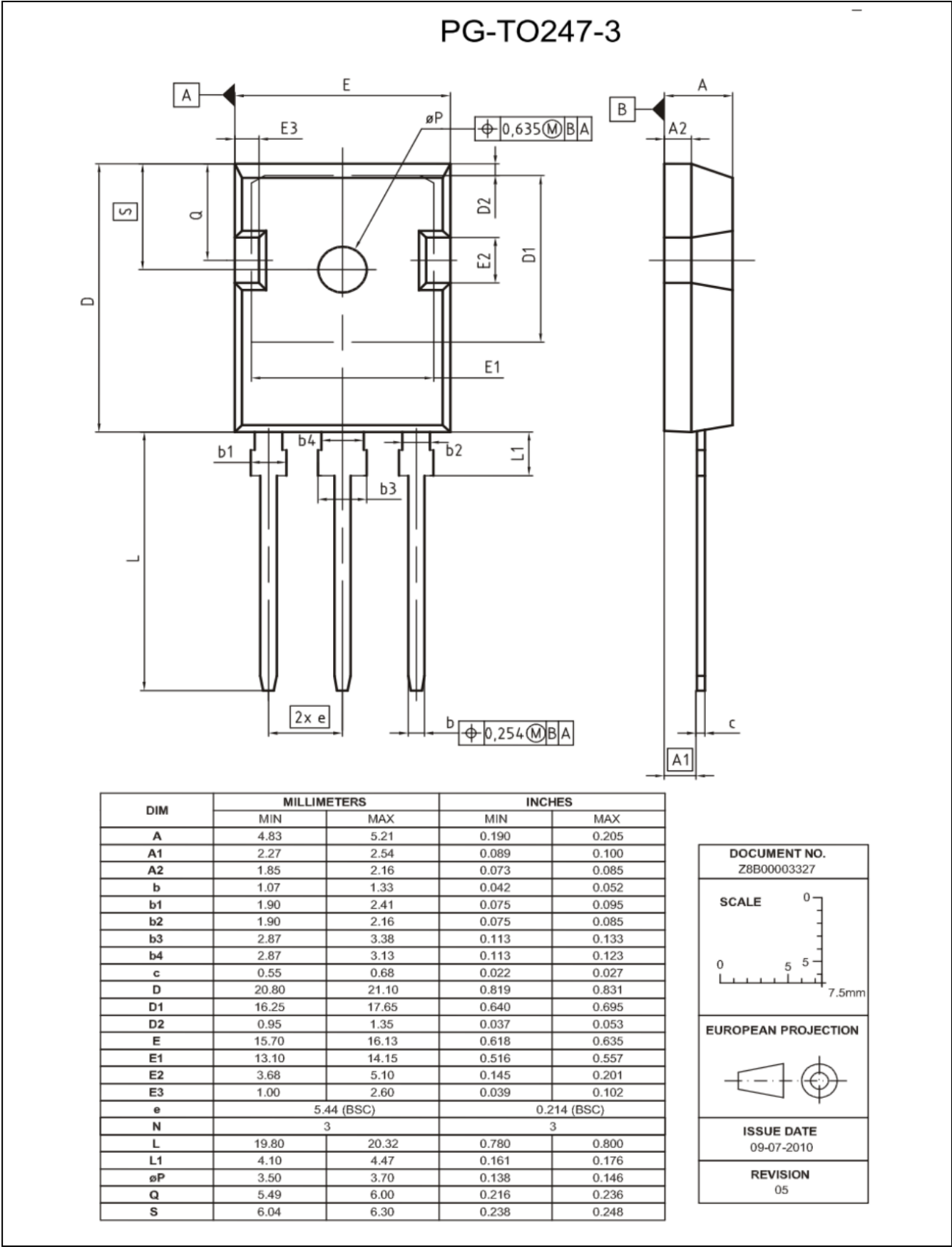


图 22 封装图

测试条件

6 测试条件

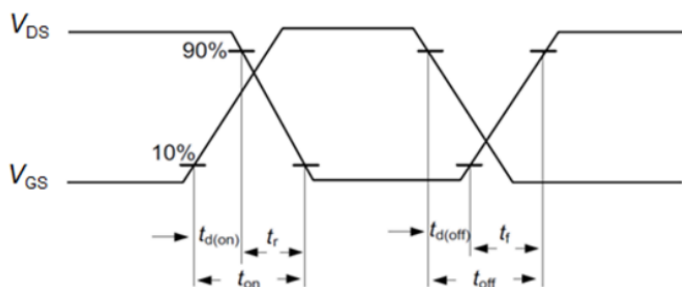


Figure A. Definition of switching times

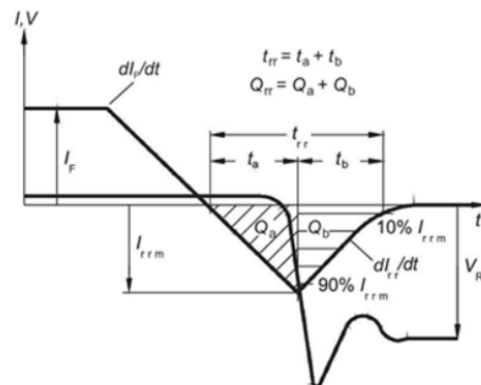


Figure C. Definition of diode switching characteristics

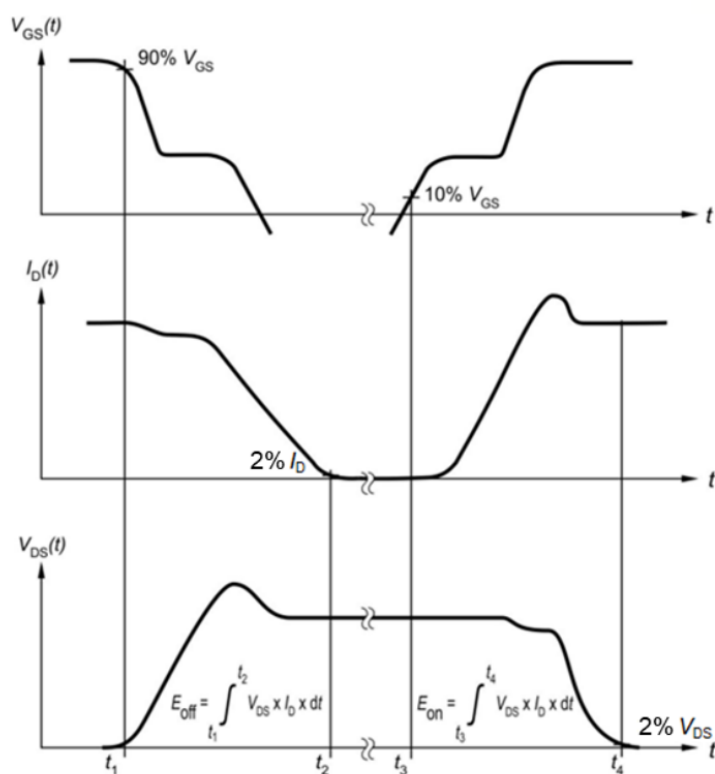


Figure B. Definition of switching losses

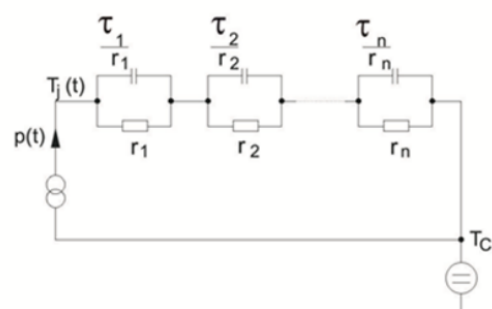


Figure D. Thermal equivalent circuit

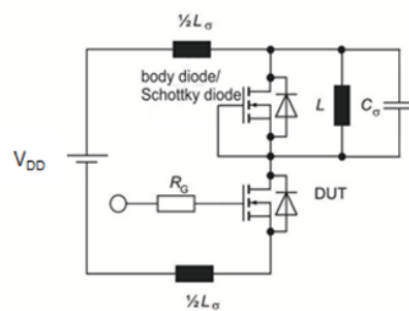


Figure E. Dynamic test circuit

Parasitic inductance L_{σ} ,
parasitic capacitor C_{σ} ,

图 23 测试条件

修订记录

修订记录

Document version	Date of release	Description of changes
2.0	2019-08-22	Final Datasheet
2.1	2019-12-10	<ul style="list-style-type: none">Move the short circuit time from dynamic characteristics table 5 to maximum ratings table 2.Update the Figure 12, 13, 14 the body diode forward voltage.
2.2	2020-12-11	Correction of circuit symbol on page 1

Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

Published by

Infineon Technologies AG

81726 München, Germany

© Infineon Technologies AG 2019.

All Rights Reserved.

Important notice

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

Please note that this product is not qualified according to the AEC Q100 or AEC Q101 documents of the Automotive Electronics Council.

Warnings

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.



免责声明

请注意，本文件的原文使用英文撰写，为方便客户浏览英飞凌提供了中文译文。该中文译文仅供参考，并不可作为任何论点之依据。

由于翻译过程中可能使用了自动化程序，以及语言翻译和转换过程中的差异，最后的中文译文与最新的英文版本原文含义可能存在不尽相同之处。

因此，我们同时提供该中文译文版本的最新英文原文供您阅读，请参见 <http://www.infineon.com>

英文原文和中文译文版本之间若存有任何歧异，以最新的英文版本为准，并且仅认可英文版本为正式文件。

您如果使用本文件，即表示您同意并理解上述说明。英飞凌不对因翻译过程中可能存在的任何不完整或不准确信息而产生的任何直接或间接损失或损害负责。英飞凌不承担中文译文版本的完整性和准确性责任。如果您不同意上述说明，请不要使用本文件。

Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

版本 2026-09-23

Infineon Technologies AG 出版，
德国 Neubiberg 85579

版权 © 2026 Infineon Technologies AG
及其关联公司。
保留所有权利。

Do you have a question about this
document?

Email:

erratum@infineon.com

重要通知

Infineon Technologies AG 及其关联公司（以下简称“英飞凌”）销售或提供和交付的产品（可能也包括样品，且可能由硬件或软件或两者组成）（以下简称“产品”），应遵守客户与英飞凌签订的框架供应合同或其他书面协议的条款和条件，如无上合同或其他书面协议，则应遵守适用的英飞凌销售条件。只有在英飞凌明确书面同意的情况下，客户的一般条款和条件或对适用的英飞凌销售条件的偏离才对英飞凌具有约束力。

为避免疑义，英飞凌不承担侵犯第三方权利的所有保证和默示保证，例如对特定用途/目的的适用性或适销性的保证。

英飞凌对与样品、应用或客户对任何产品的具体使用有关的任何信息或本文件中给出的任何示例或典型值概不负责。

本文件中包含的数据仅供具有技术资格和技能的客户代表使用。客户有责任评估产品对预期应用和客户特定用途的适用性，并在预期应用和客户特定用途中验证本文件中包含的所有相关技术数据。客户有责任正确设计、编程和测试预期应用的功能性和安全性，并遵守与其使用相关的法律要求。

除非英飞凌另行明确批准，否则产品不得用于任何因产品故障或使用产品的任何后果可合理预期会导致人身伤害的应用。但是，上述规定并不妨碍客户在英飞凌明确设计和销售的使用领域中使用任何产品，但是客户对应用负有全部责任。

英飞凌明确保留根据适用法律，如《德国版权法》（UrhG）第 44b 条，将其内容用于商业资料和数据勘探（TDM）的权利。

如果产品包含安全功能：

由于任何计算设备都不可能绝对安全，尽管产品采取了安全措施，但英飞凌不保证产品不会被入侵、数据不会被盗或遗失，或不会发生其他漏洞（以下简称“安全漏洞”），英飞凌对任何安全漏洞不承担任何责任。

如果本文件包含或引用软件：

根据美国、德国和世界其他国家的知识产权法律和条约，该软件归英飞凌所有。英飞凌保留所有权利。因此，您只能按照软件附带的软件授权协议的规定使用本软件。

如果没有适用的软件授权协议，英飞凌特此授予您个人的、非排他性的、不可转让的软件知识产权授权（无权转授权）：(a) 对于以源代码形式提供的软件，仅在贵组织内部修改和复制该软件用于英飞凌硬件产品；及 (b) 对于以二进制代码 (binary code) 形式对外向终端用户分发该软件，仅得用于英飞凌硬件产品。禁止对本软件进行任何其他使用、复制、修改、翻译或编译。有关产品、技术、交货条款和条件以及价格的详细信息，请联系离您最近的英飞凌办公室或访问 <https://www.infineon.com>。